Sheet <u>1</u> of <u>2</u> Substitute Form PTO-1449 Application No. U.S. Department of Commerce Attorney's Docket No. Patent and Trademark Office 14414-019001 10/762,030 Information Disclosure Statement **Applicant** by Applicant
Use several sheets if necessary) Raluca Dinu et al. Filing Date **Group Art Unit** 292 January 21, 2004 X37 CFR \$1.0 **U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date
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	AB	5,198,513	03/30/93	Clement et al.		_	
	AC	5,219,788	06/15/93	Abernathey et al.			
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next communication to applicant.					

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(37 CFR §1.98(b))

U.S. Patent Documents

Examiner Desig. Document Publication

Attomey's Docket No. 14414-019001	Application No. 10/762,030	
Applicant Raluca Dinu et al.		
Filing Date	Group Art Unit	_

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	AEE	10/264,461	N/A	Dinu et al.		_	
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1	АНН	10049443	02/20/98	JP			Х	
	AII	2001255426	09/21/01	JР		(x	
	AJJ	09258151	10/03/97	JP		(х	
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TA	ALL	04238305	08/26/92	JР			χ.	

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	ANN	Chen et al., "Thermosetting Polyurethanes with Stable and Large Second-Order Optical Nonlinearity," Macromolecules, 1992, 25:4032-4035	
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	AQQ	Ma et al., "Highly Efficient and Thermally Stable Nonlinear Optical Dendrimer for Electrooptics," <u>J. Am. Chem. Soc.</u> , 2001, 123:986-987	
	ARR	Mao et al., "Progress toward Device-Quality Second-Order Nonlinear Optical Materials. 1. Influence of Composition and Processing Conditions on Nonlinearity, Temporal Stability, and Optical Loss," Chem. Mater., 1998, 10:146-155	
	ASS	Oh et al., "Electro-optic polymer modulators for 1.55 μ m wavelength using phenyltetraene bridged chromophore in polycarbonate," Appl. Phys. Lett., 2000, 76(24):3525-3527	
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